

PROJECT ADMINISTRATION DATA SHEET

ORIGINAL REVISION NO. _____

Project No. G-41-617 (R5842-OAD) GTRI/~~OM~~ DATE 10 / 30 / 84

Project Director: R. A. Young School/~~ENG~~ Physics

Sponsor: ~~ENGELHARD~~ Freeport Kaolin Company

Type Agreement: P. O. #P-0046

Award Period: From 10/1/84 To 12/31/84 (Performance) 12/31/84 (Reports)

Sponsor Amount: This Change 12/31/87 Total to Date

Estimated: \$ 6,452 \$ 6,452

Funded: \$ 6,452 \$ 6,452

Cost Sharing Amount: \$ N/A Cost Sharing No: _____

Title: Diffraction Studies of Trace Minerals

ADMINISTRATIVE DATA

1) Sponsor Technical Contact:
T. R. Drummond
~~ENGELHARD~~ Freeport Kaolin Company
P. O. Box 37
Gordon, GA 31031
(912) 628-7011

OCA Contact R. Dennis Farmer x-4820
2) Sponsor Admin/Contractual Matters:
Ben L. Creamer see Rpt #3
~~Freeport Kaolin Company~~
P. O. Box 37
Gordon, GA 31031
(912) 628-7136

Defense Priority Rating: _____ Military Security Classification: _____
(or) Company/Industrial Proprietary: N/A

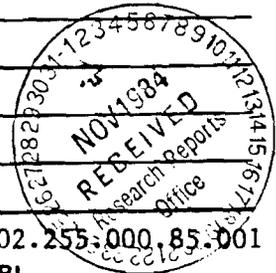
RESTRICTIONS

See Attached _____ Supplemental Information Sheet for Additional Requirements.

Travel: Foreign travel must have prior approval - Contact OCA in each case. Domestic travel requires sponsor approval where total will exceed greater of \$500 or 125% of approved proposal budget category.

Equipment: Title vests with none proposed

COMMENTS:



COPIES TO:

- Project Director
- Research Administrative Network
- Research Property Management
- Accounting

- Procurement/EES Supply Services
- Research Security Services
- Reports Coordinator (OCA)
- Research Communications (2)

Sponsor ID #02.255.000.85.001

- GTRI
- Library
- Project File
- Other A. Jones



College of Sciences and Liberal Studies
School of Physics
24 January 1985

Mr. Paul Sennett
Director of Research and Development
Freeport Kaolin Company
P. O. Box 337
Gordon, GA 31031

Ref: P-0046
Project G41-617
"Diffraction Studies of Trace Minerals"
1 October 1984-31 December 1984

Dear Paul,

Although this project was supposed to start on 1 October 1984 and monthly letter progress reports were to be rendered, no previous report has been rendered because of the uncertainties and delays occasioned by the departure of Catherine Dentan and the apparent difficulty at Freeport in getting someone to replace her as the one permanently in charge of the project at Freeport. As one consequence, we have not received from Freeport any samples other than those that Catherine left with us last July.

Last fall, you told us to go ahead and start with two of the samples that she had left. Since time was available on the diffractometer and no other specimens have been supplied as yet by Freeport, we have in fact examined all six of those that she left: GF122W, GF122FINE, BF122W, BF122FINE, MT MILLED and MIXED LAYER.

Attached are reduced-size xerox copies of our diffractometer traces from $5-32^\circ$ (2θ) made with copper $K\alpha$ radiation. As you see, and as I believe Hans Neubold remarked when you visited last, the general impression is that the quality of the data is very high. That correct impression is ascribable to the fact that we have used a step-scan mode with rather small steps and relatively long times spent accumulating counts at each step.

In Figures 2-6 the b figure was produced from the same data used for the a figure by a 5X computer expansion of the vertical scale. Because of the noise, very little more is seen in the expanded figures than in the original. However, it may be possible to see more in the expanded pattern if we first did something like 4-point computer smoothing of the data. We have not yet tried that. For example, such smoothing in the expanded pattern might make it clearer whether the possible small amounts of montmorillinite and mica are actually present and, if so, in what degree the amounts differ from sample to sample.

At first glance it seems that the amount of montmorillinite in GF122FINE may be greater than that in GF122W while the converse is true for the mica content. It does seem relatively clear that there is more anatase in GF122W than in GF122FINE.

Letter to Paul Sennett
Page 2

It also appears that the amount of layer faulting is greater in the FINE fraction than in the whole fraction of GF122. One might like to check that by running other diffraction patterns of separately packed specimens of the same materials. Again, in BF122 it appears that the amount of layer faulting (lack of "degree of crystal energy") is slightly greater in the FINE fraction than in the whole material.

In both GF122 and BF122 the 00 ℓ lines are sharper in the W material than in the FINE fraction. This may be associated more with the greater amount of layer faulting in the FINE fraction than with the reduction in average particle size. As you know, one of the faults that various workers have attempted to model for layer-faulted kaolinite is a variation in the spacing between layers. That is not from any intercalated species but simply from the faults in the kaolinite itself.

In the MIXED LAYER material, it is obvious that there is considerable montmorillinite present and some anatase. Anatase is more obvious in this pattern (Figure 5) than in that of the 122 patterns, largely because the kaolinite 00 ℓ peaks are so very sharp--probably approaching instrumental resolution. It is interesting that these kaolinite peaks are so sharp, since the kaolinite in this material is also "poorly crystallized", approximately as much so as are either BF122FINE or GF122FINE, the two specimens which show the broadest 00 ℓ kaolinite peaks.

In the MT MILLED specimen, we see many things besides kaolinite. In fact the strongest peak present seems to belong to muscovite. Of possible particular interest for this specimen is the fact that two polymorphs of muscovite, 3T and 2M, were present. Also, probably present are quartz and a small amount of anatase. It may be of interest to note that the 003 muscovite 3T line at about 9° is sharper than the 001 kaolinite line at just over 12°. That suggests very good stacking of the muscovite in the c* direction.

We hope you will find these results interesting, and that some of them may be of possible use to you.

Although we have not received any additional samples from you, it is not a problem to us at the moment; Paul Switch, who does most of the work, has had to drop out of school for this quarter and go to New Jersey because of his father's grave illness. He may not be able to return to Atlanta until the end of March.

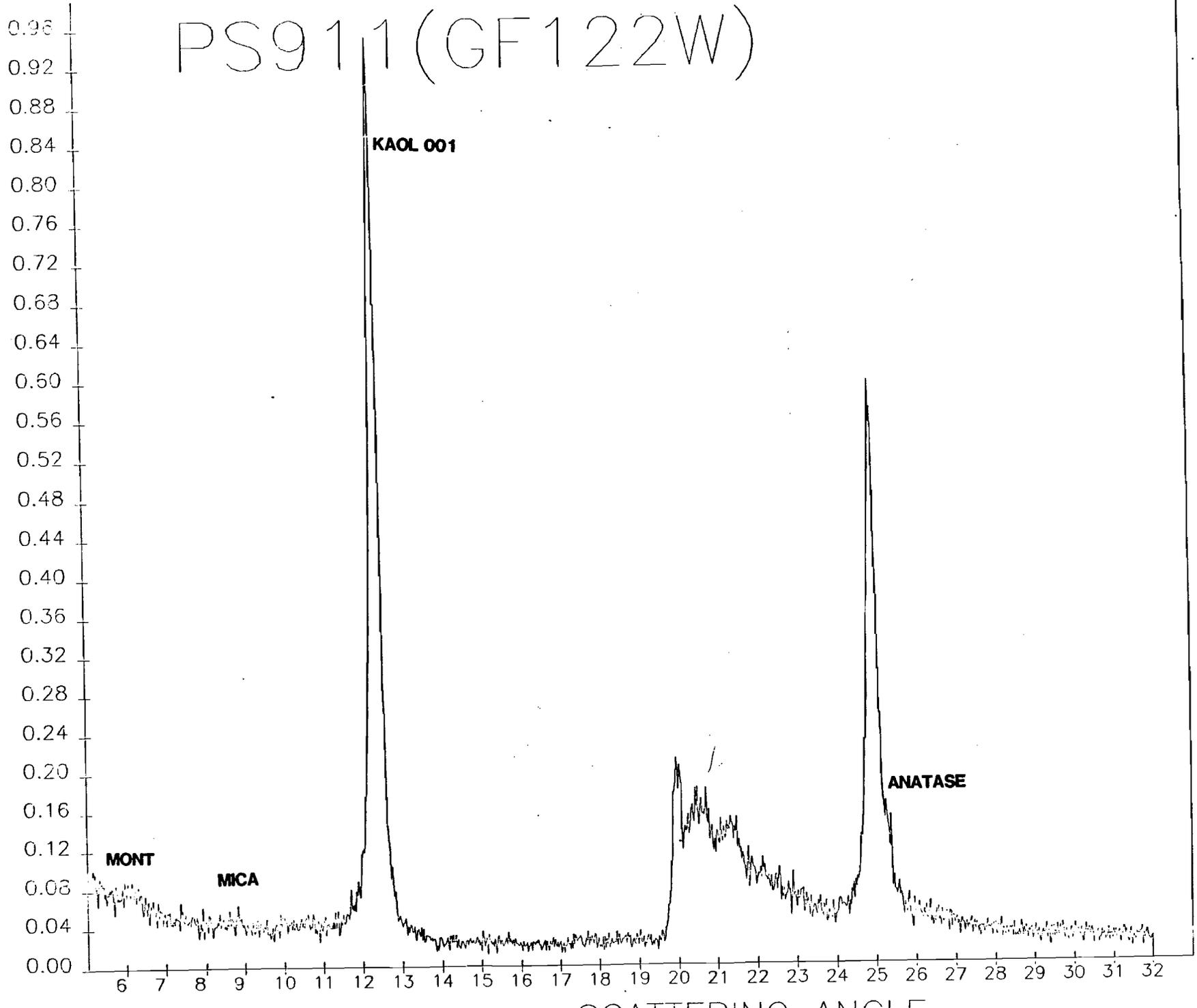
Sincerely,

R. A. Young,
Professor

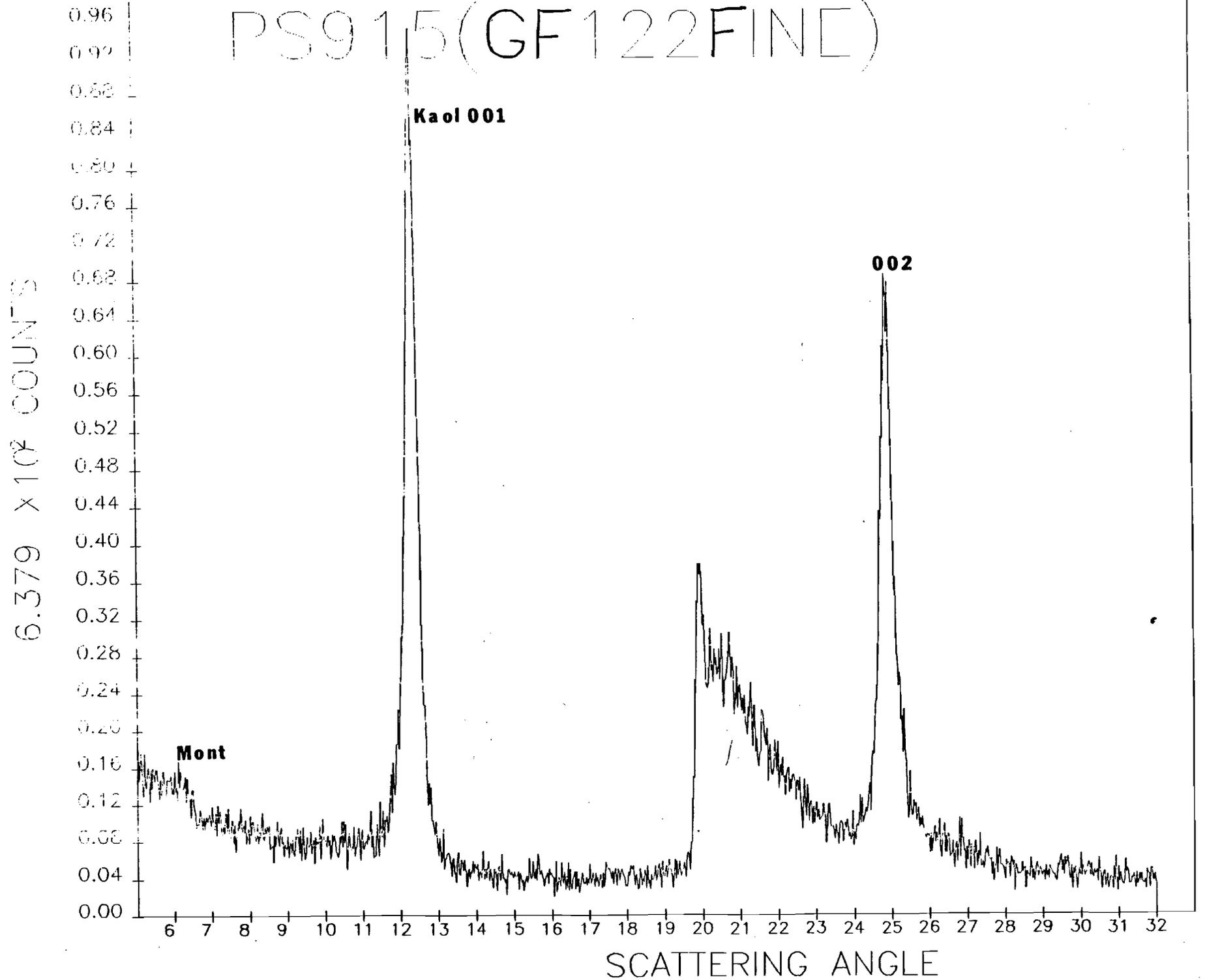
RY:rg
Encl.
xc: Paul Switch w/encl.

PS911 (GF122W)

1.101 X 10³ COUNTS

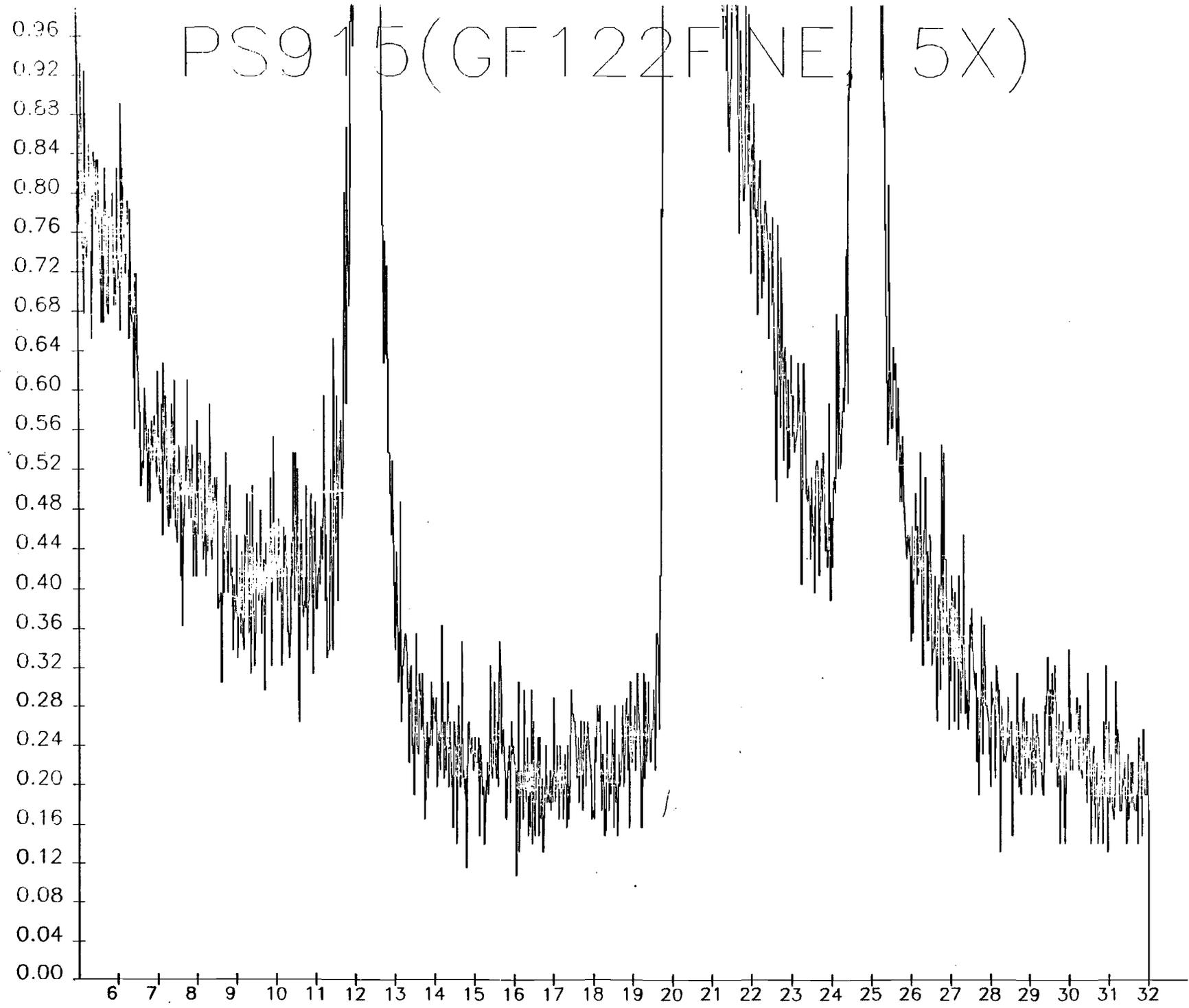


PS915(GF122FINE)



PS915(GF122FINE 5X)

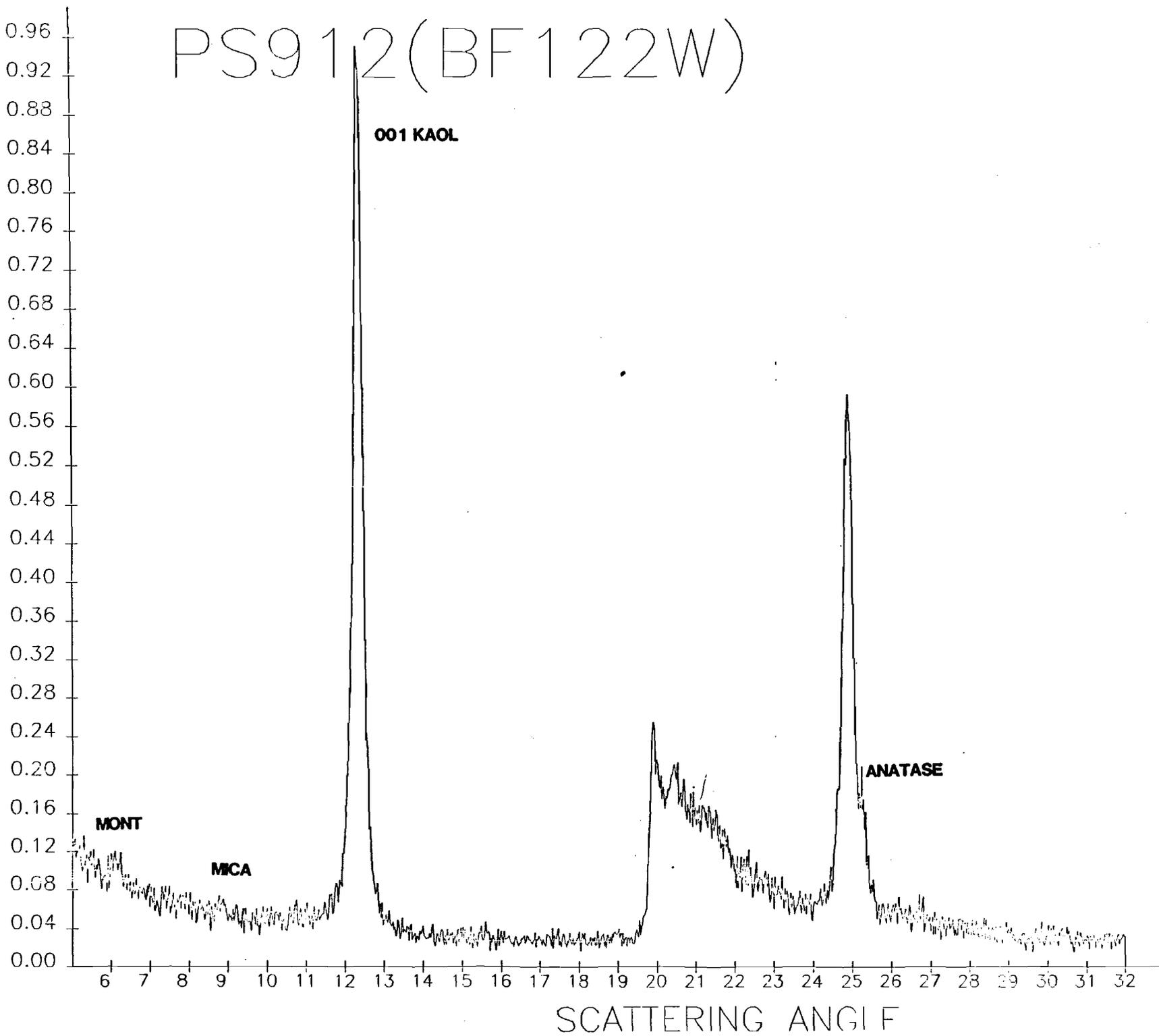
1.212 X10² COUNTS



SCATTERING ANGLE

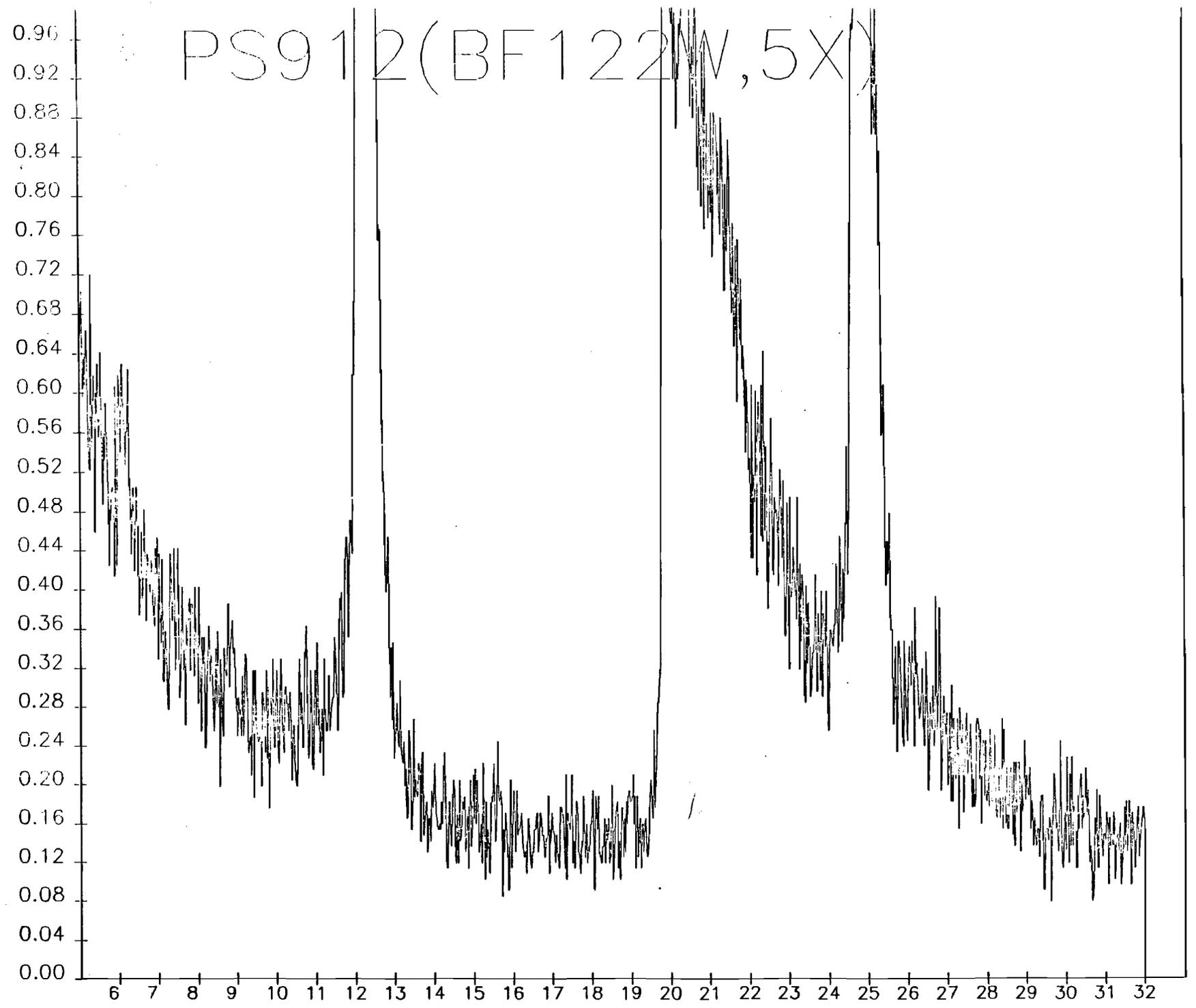
PS912(BF122W)

9.284 X10² COUNTS



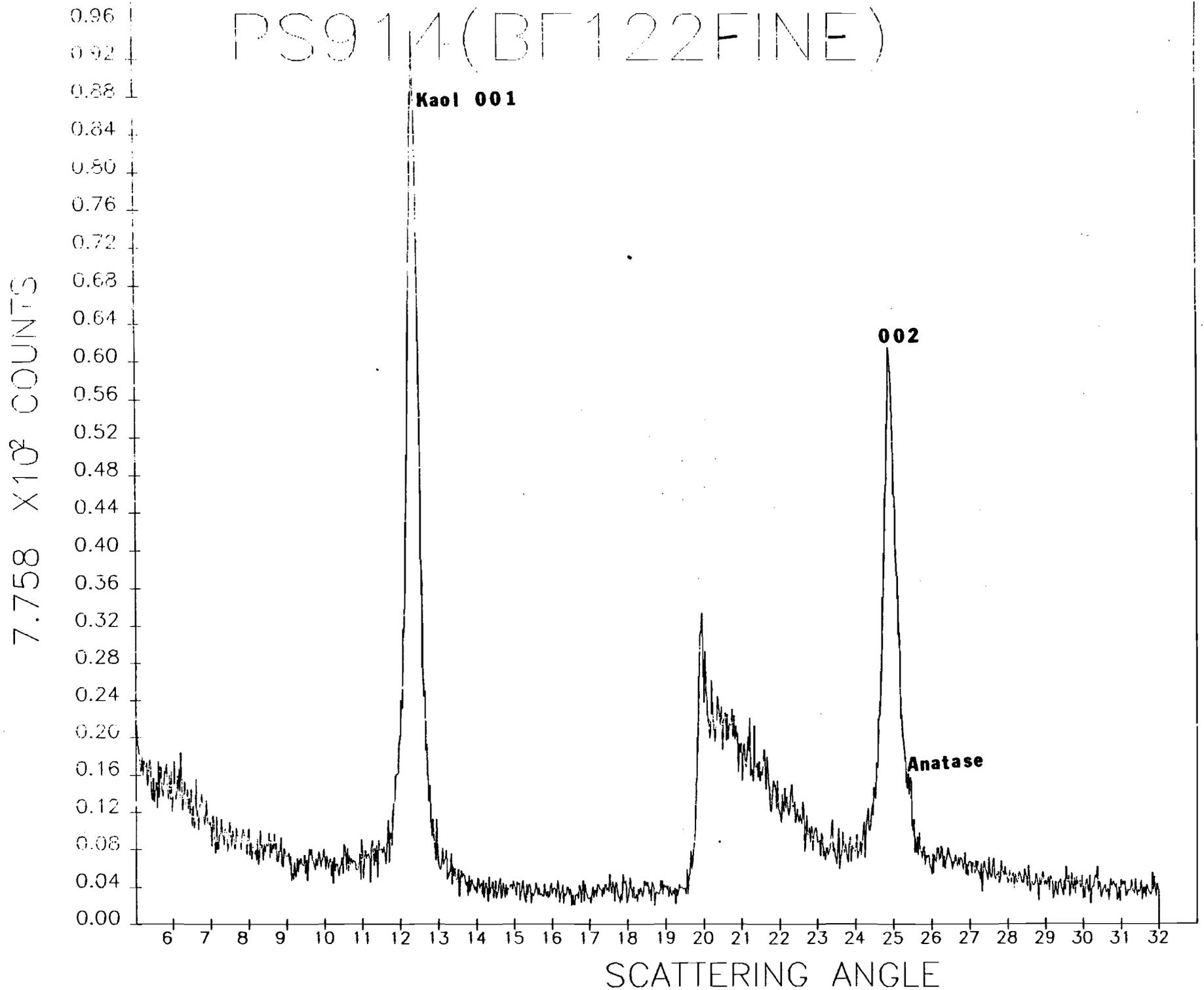
PS912(BF122W,5X)

1.764 X 10² COUNTS



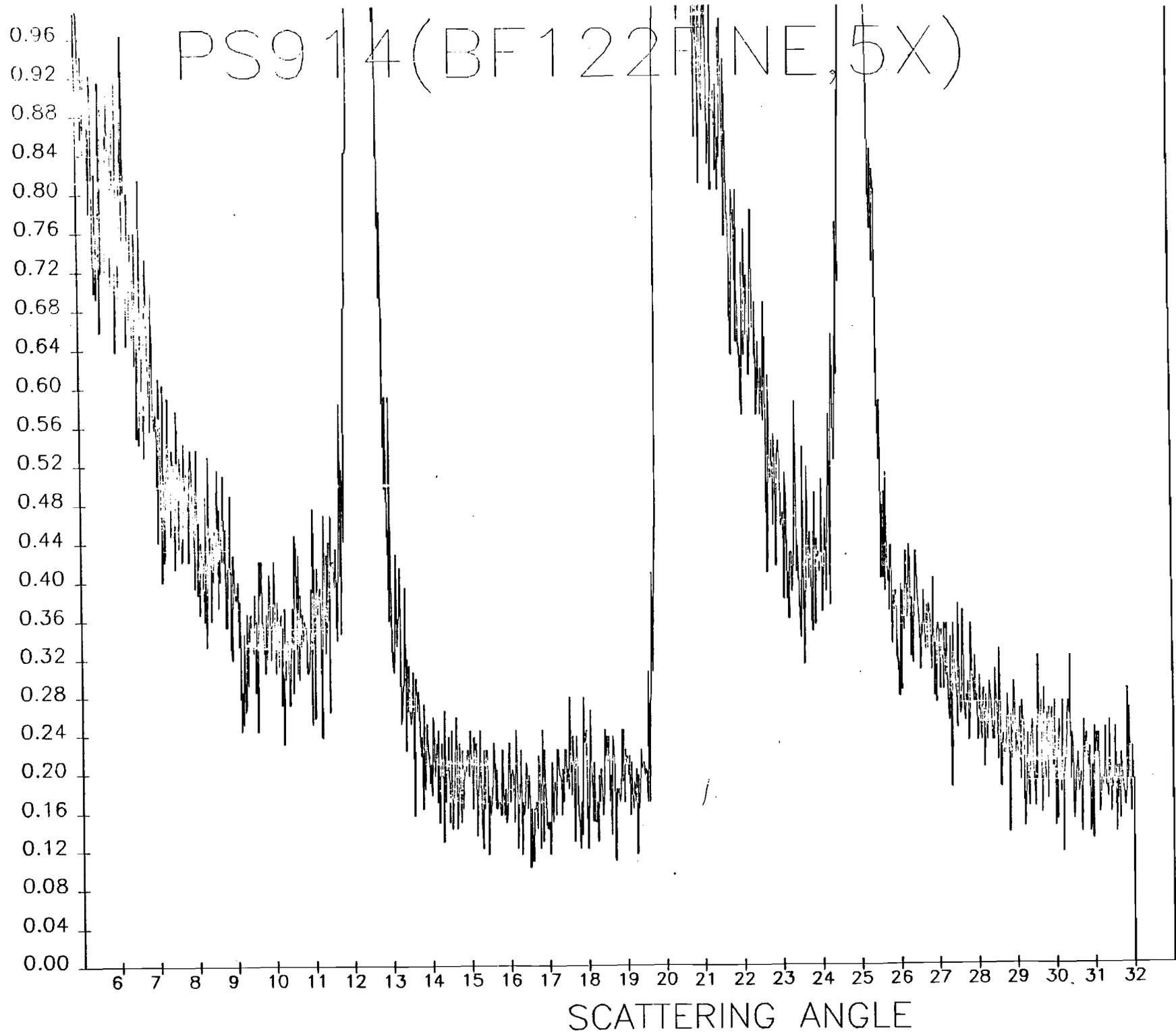
SCATTERING ANGLE

PS914(BF122FINE)

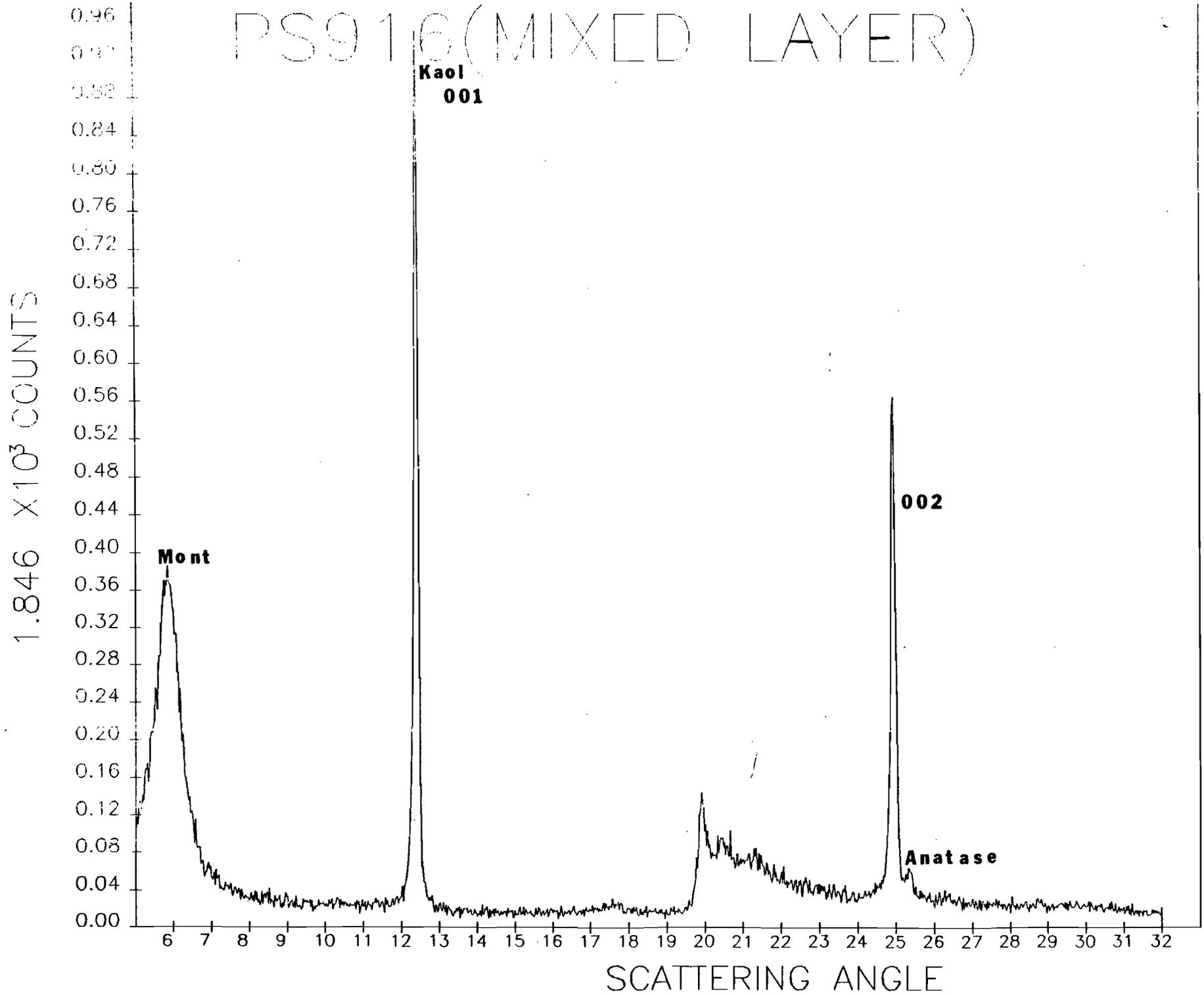


PS914(BF122FINE,5X)

1.474 X 10² COUNTS

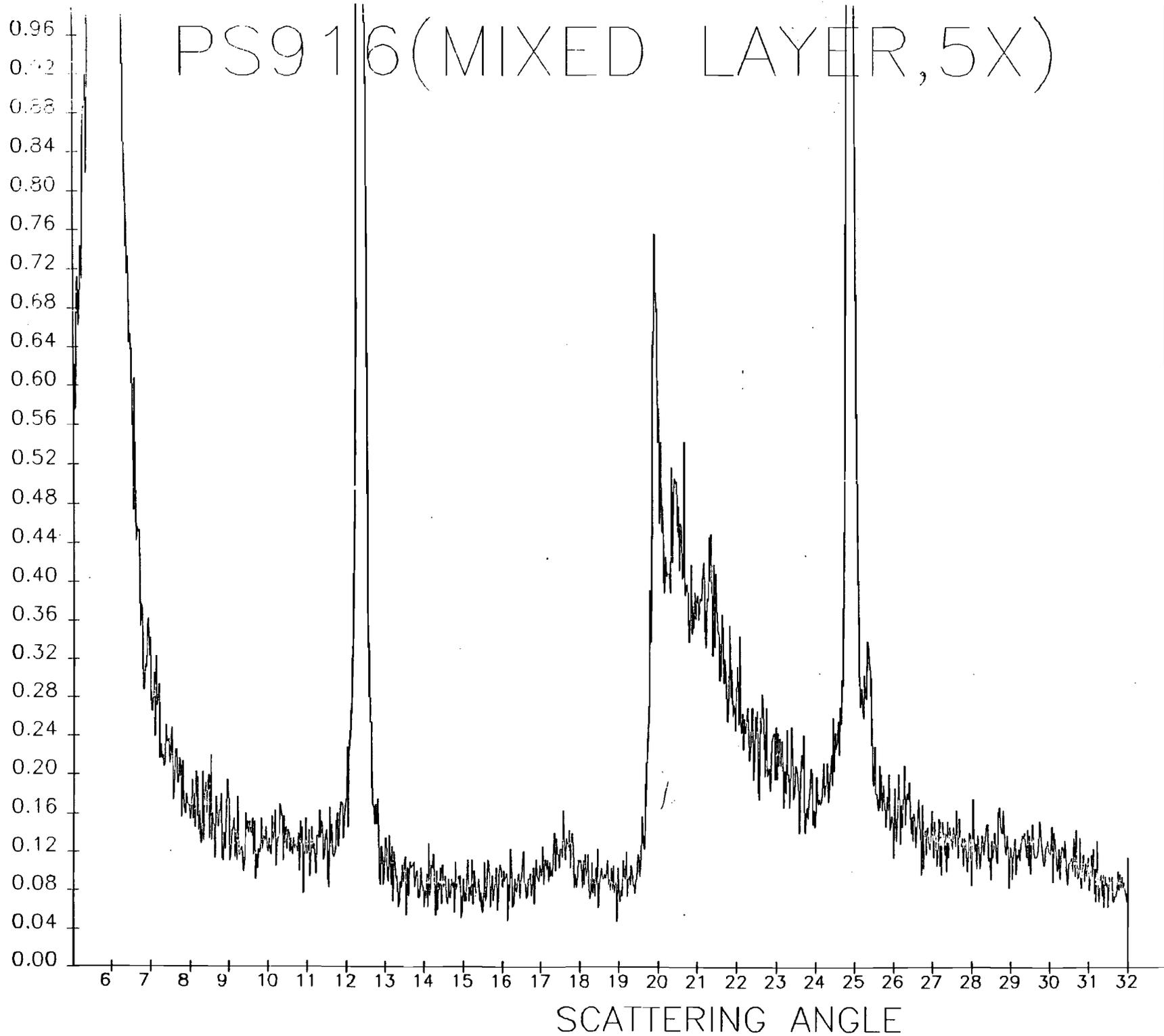


PS916 (MIXED LAYER)

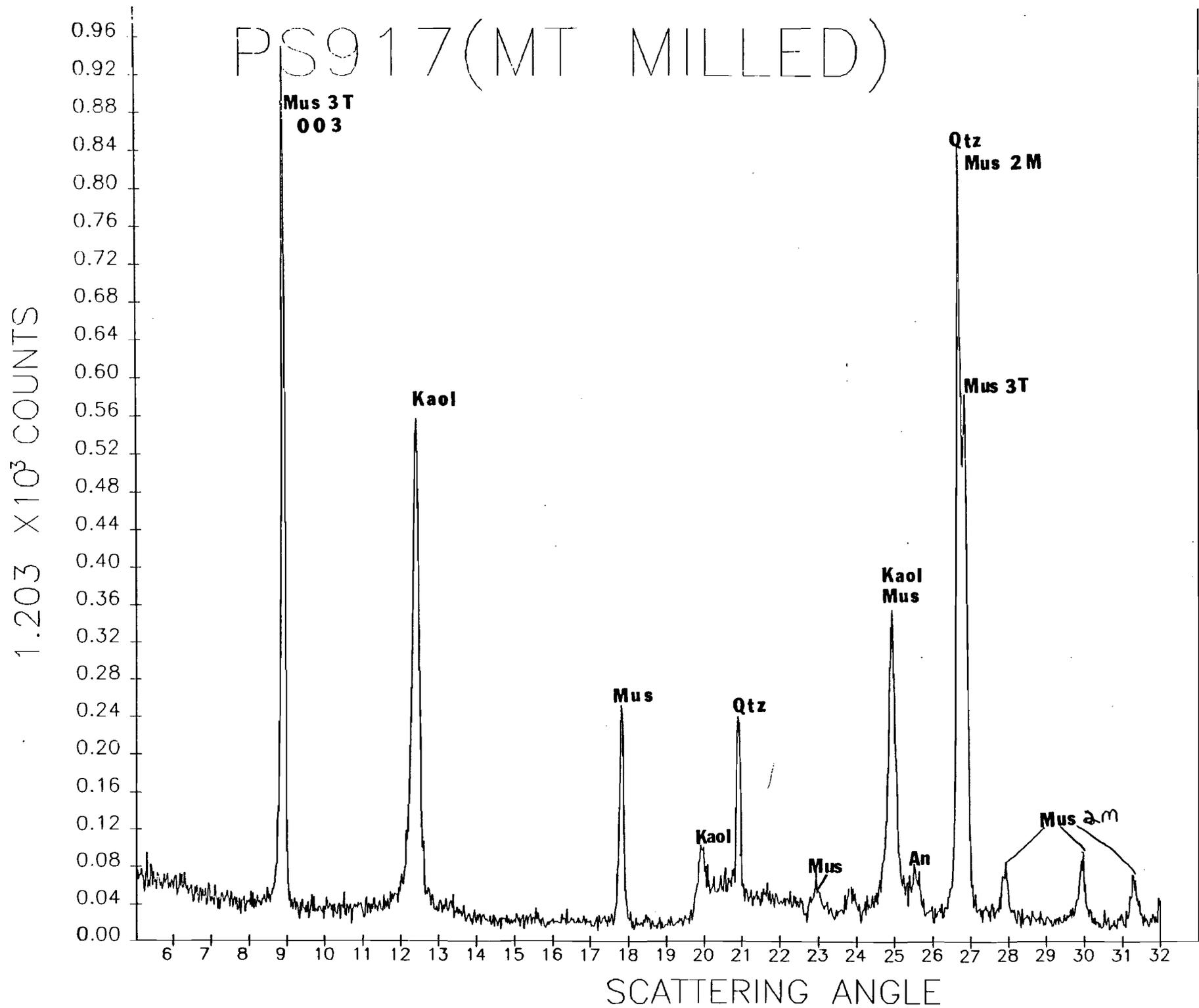


PS916 (MIXED LAYER, 5X)

3.508 X 10² COUNTS



PS917(MT MILLED)



2.286 X 10² COUNTS

PS917 (MT MILLED, 5X EXP)

